

Experimental conditions of channel doping

with respect to the silicon-cotaining amorphous semiconductor film

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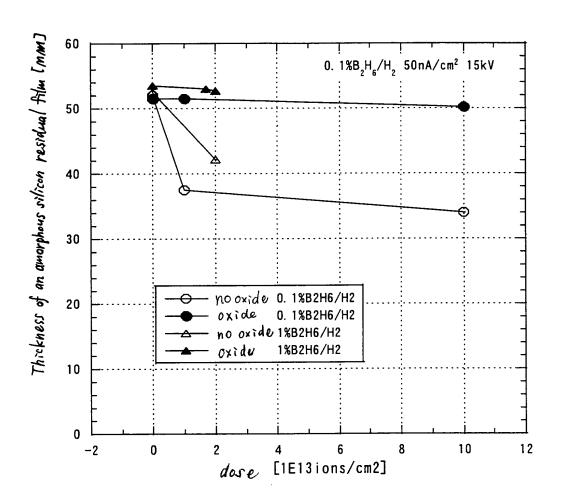
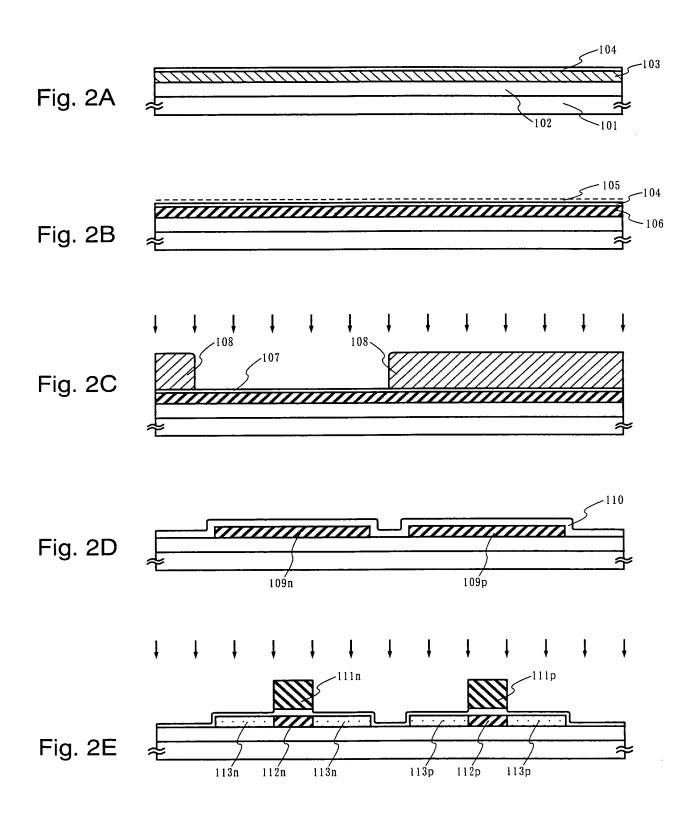
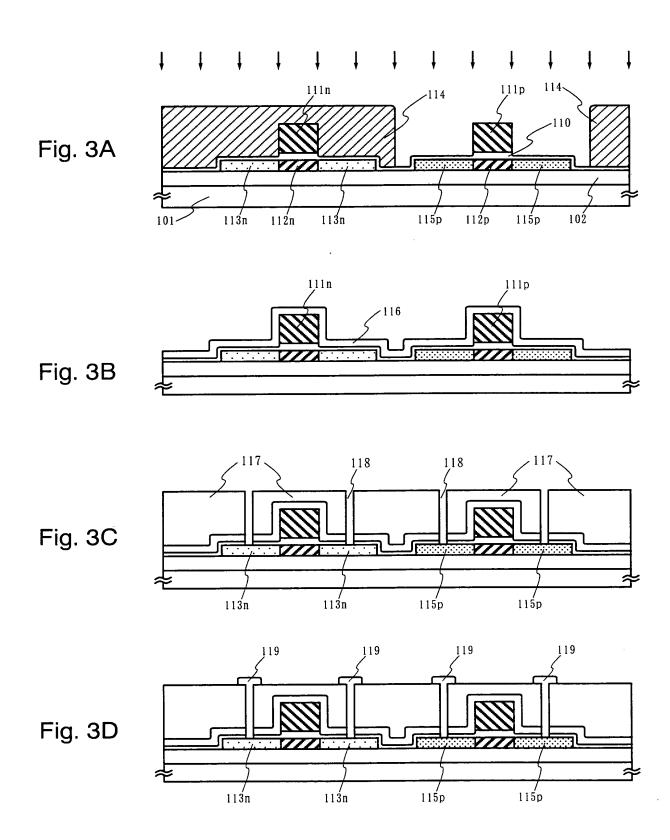


Fig. 1





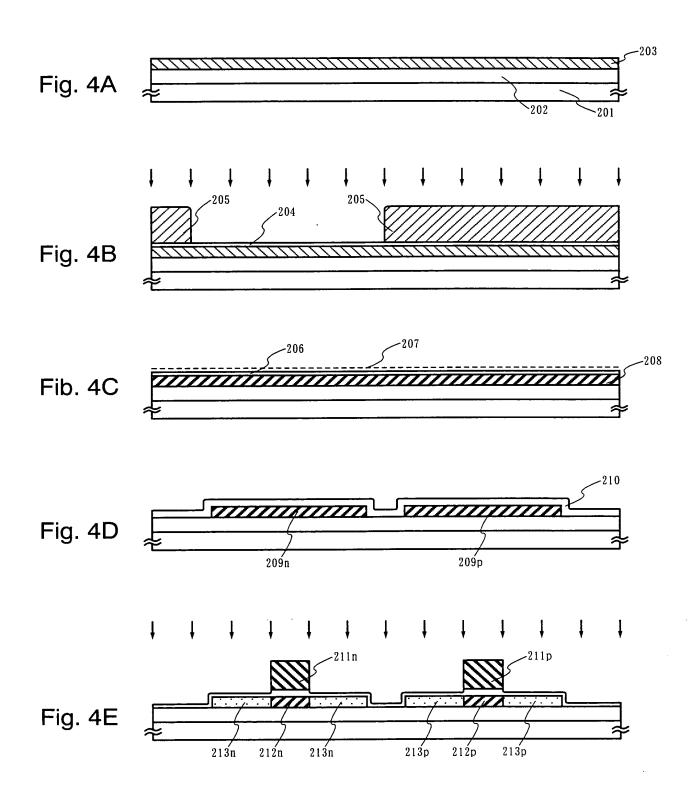


Fig. 5A

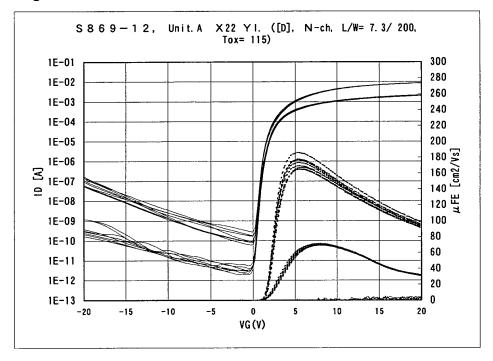
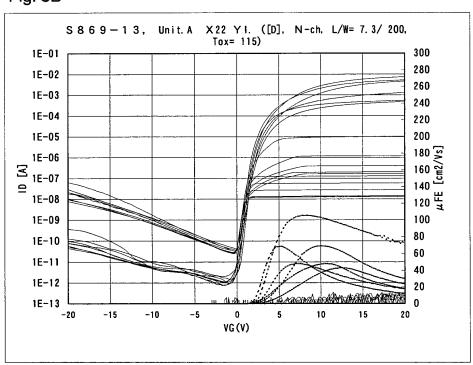
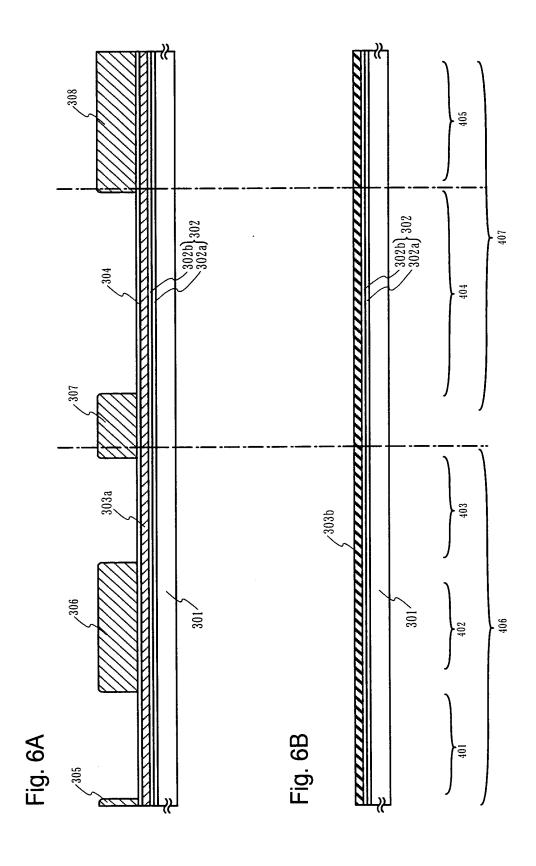
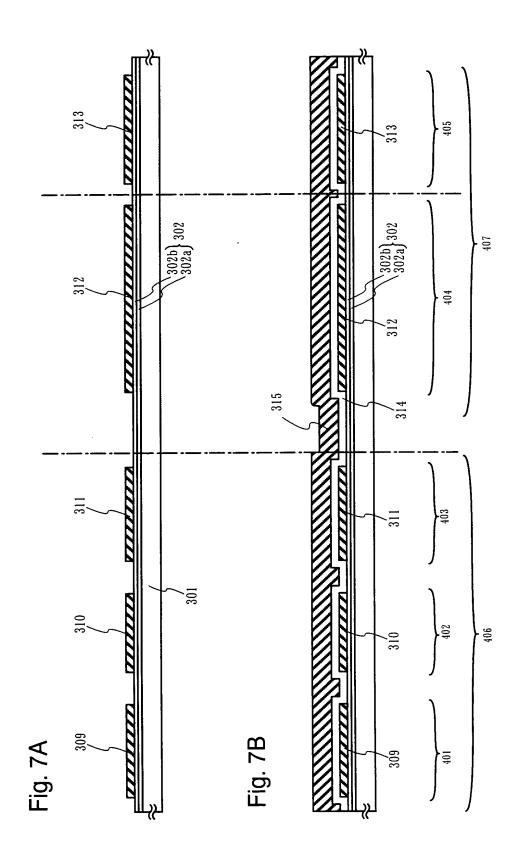


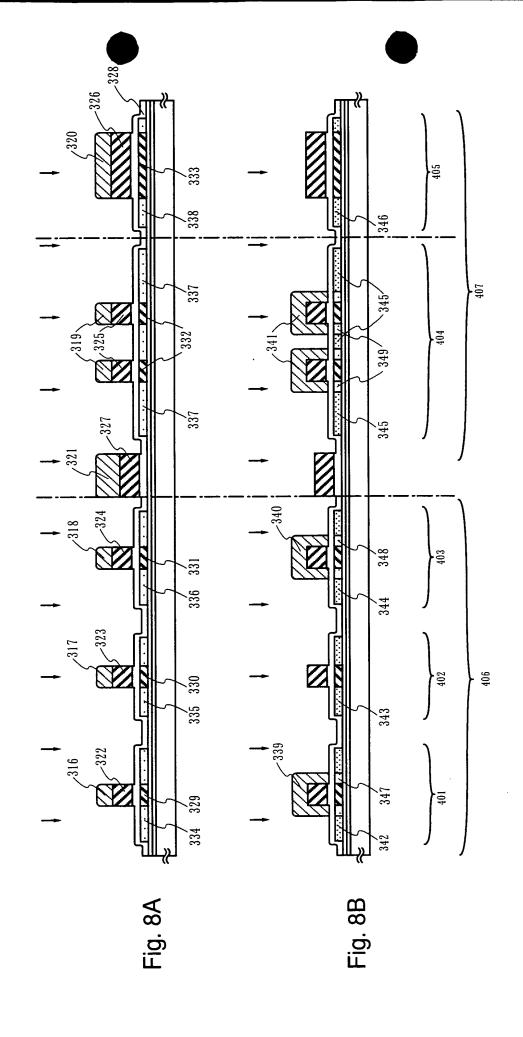
Fig. 5B

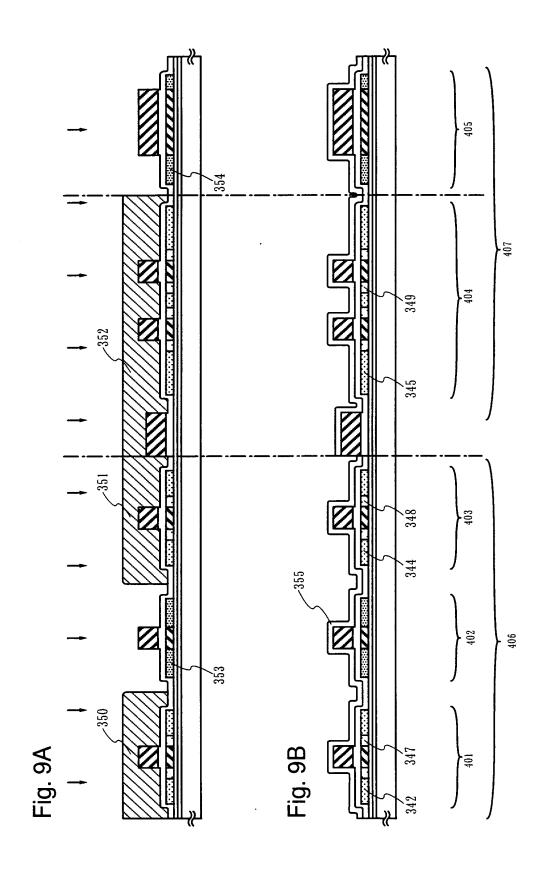


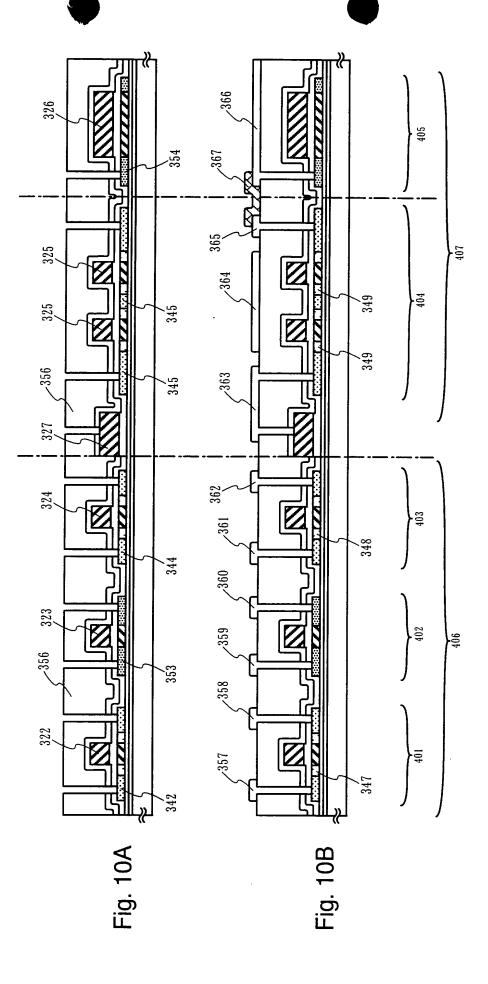
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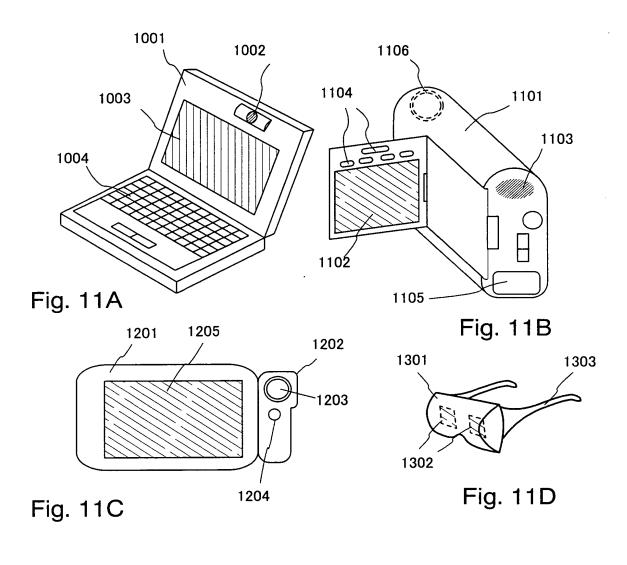












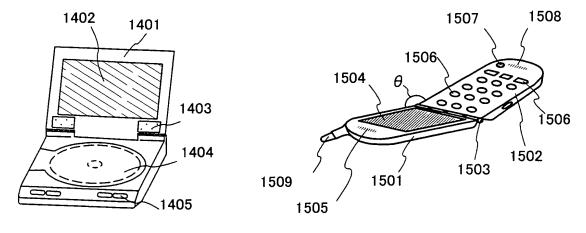
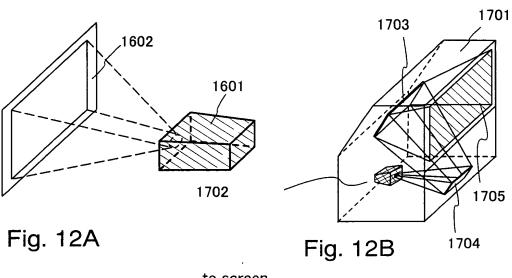


Fig. 11E

Fig. 11F



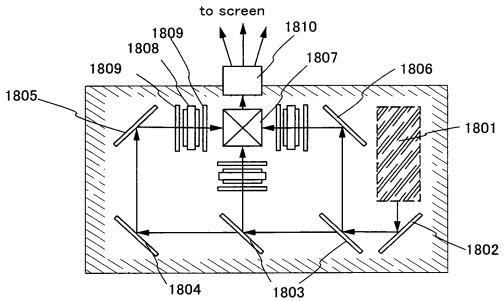


Fig. 12C

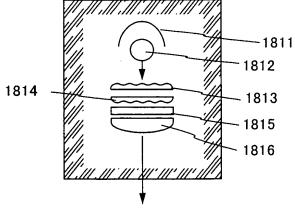


Fig. 12D



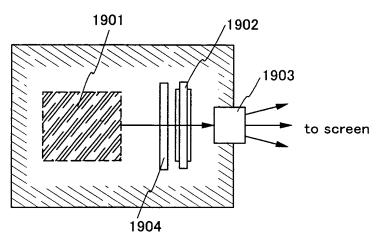


Fig. 13A

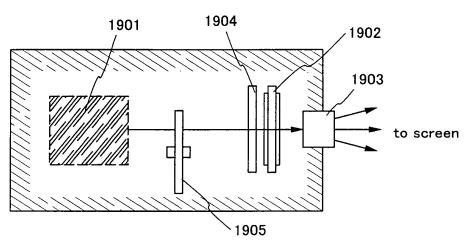


Fig. 13B

